

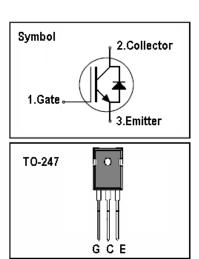
#### **IGBT**

#### **Features**

- 1200V,30A
- $V_{CE(sat)(typ.)}$ =2.2V@ $V_{GE}$ =15V, $I_{C}$ =30A
- High speed switching
- Higher system efficiency
- Soft current turn-off waveforms
- Square RBSOA using NPT technology

## **General Description**

JIAEN NPT IGBTs offer lower losses and higher energy efficiency for application such as IH (induction heating),UPS, general inverter and other soft switching applications.



### **Absolute Maximum Ratings**

Symbol	Parameter	Value	Units	
Vces	Collector-Emitter Voltage 1200 V		V	
V <sub>GES</sub>	Gate-Emitter Voltage ± 30		V	
l.	Continuous Collector Current ( Tc=25 °C)	50	Α	
lc	Continuous Collector Current (Tc=100°C)	30	А	
Ісм	I <sub>CM</sub> Pulsed Collector Current (Note 1) 90		А	
lF	I <sub>F</sub> Diode Continuous Forward Current ( T <sub>C</sub> =100 °C) 30		А	
I <sub>FM</sub>	Diode Maximum Forward Current (Note 1)	1) 90 A		
t <sub>sc</sub>	t <sub>sc</sub> Short Circuit Withstand Time 10 u		us	
Ъ	Maximum Power Dissipation ( Tc=25 °C)	260	W	
P <sub>D</sub>	Maximum Power Dissipation ( Tc=100°C)	105	W	
TJ	Operating Junction Temperature Range	-55~150 ℃		
Tstg	Storage Temperature Range	orage Temperature Range -55~150 ℃		

# **Thermal Characteristics**

Symbol	Parameter	Max.	Units
R <sub>th j-c</sub> Thermal Resistance, Junction to case for IGBT 0.48 °C/			°C/W
R <sub>th j-c</sub> Thermal Resistance, Junction to case for Diode 0.83		°C/W	
R <sub>th j-a</sub>	R <sub>th j-a</sub> Thermal Resistance, Junction to Ambient		℃/W



# JNG30N120HS2

# $\underline{\textbf{Electrical Characteristics}} \text{ (Tc=25\,^{\circ}C unless otherwise noted )}$

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	$V_{GE} = 0V, I_{C} = 250uA$	1200	-	-	V
I <sub>CES</sub>	Collector-Emitter Leakage Current	V <sub>CE</sub> = 1200V, V <sub>GE</sub> = 0V	-	-	250	uA
	Gate Leakage Current, Forward	$V_{GE}$ =30V, $V_{CE}$ = 0V	-	-	100	nA
GES	Gate Leakage Current, Reverse	$V_{GE}$ = -30V, $V_{CE}$ = 0V	-	-	-100	nA
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}$ , $I_C = 250uA$	4.0	5.0	6.0	V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	$V_{GE}$ =15V, $I_{C}$ = 30A	-	2.2	2.6	V
Qg	Total Gate Charge	V <sub>CC</sub> =960V V <sub>GE</sub> =15V	-	165		nC
Q <sub>ge</sub>	Gate-Emitter Charge		-	33		nC
Qgc	Gate-Collector Charge	Ic=30A	-	70		nC
t d(on)	Turn-on Delay Time	Vcc=600V	1	25	-	ns
t r	Turn-on Rise Time		•	53	-	ns
t d(off)	Turn-off Delay Time	V <sub>GE</sub> =15V	-	323	-	ns
t f	Turn-off Fall Time	I <sub>C</sub> =30A R <sub>G</sub> =15Ω	-	84	-	ns
Eon	Turn-on Switching Loss	Inductive Load	1	1.72	-	mJ
Eoff	Turn-off Switching Loss	T <sub>C</sub> =25 ℃	-	1.45	-	mJ
Ets	Total Switching Loss		-	3.17	-	mJ
C <sub>ies</sub>	Input Capacitance	V <sub>CE</sub> =25V	-	1600	-	pF
Coes	Output Capacitance	V <sub>GE</sub> =0V	1	270	-	pF
C <sub>res</sub>	Reverse Transfer Capacitance	f = 1MHz	-	170	-	pF

# Electrical Characteristics of Diode (Tc=25°C unless otherwise noted)

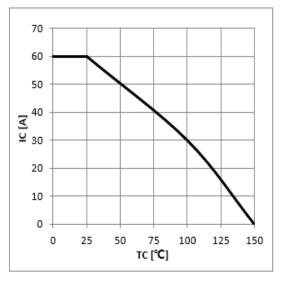
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> =30A	-	2.1	2.4	V
trr	Diode Reverse Recovery Time	V <sub>CE</sub> = 600V	-	488		ns
Irr	Diode peak Reverse Recovery Current	I <sub>F</sub> = 30A	-	13.75		Α
Qrr	Diode Reverse Recovery Charge	dl <sub>F</sub> /dt = 375A/us	-	2309		nC

#### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature



# **Typical Performance Characteristics**



275 250 225 200 <u>日</u>175 Disspation 150 150 Power 75 50 25 0 25 50 75 100 150 125 TC [°C]

Figure 1: Maximum DC Collector Current VS. case temprature

Figure 2: Power Dissipation VS. Case Temperature

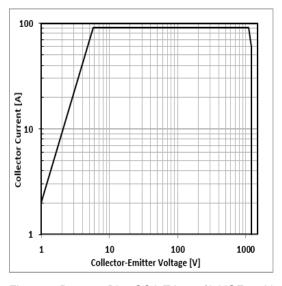


Figure 3: Reverse Bias SOA,TJ=125  $^{\circ}$ C,VGE=15V

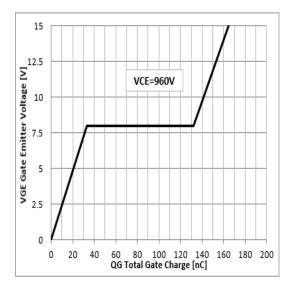


Figure 4: Typical Gate charge VS. VGE,IC=30A



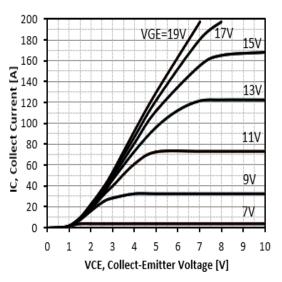


Figure 5: Typical IGBT Output characteristics,  $\label{eq:TC=25\,C;tp=300us} TC=25\,^{\circ}C;tp=300us$ 

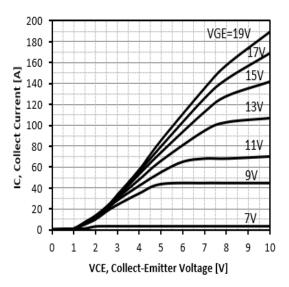


Figure 6: Typical IGBT Output characteristics, TC=150℃;tp=300us

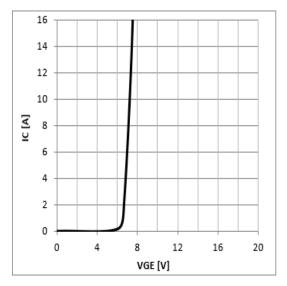


Figure 7: Typical Gate Threshold Voltage

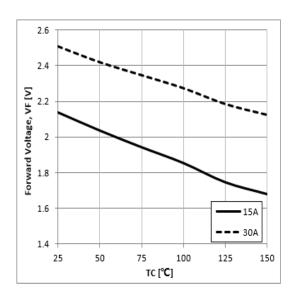


Figure 8: Typical Forward Voltage vs IF





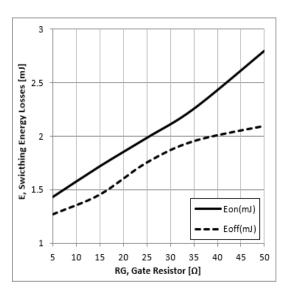


Figure 9: Typical Energy Loss VS. RG, TC=25 $^{\circ}$ C, L=100uH,VCE=600V,VGE=15V,IC=30A

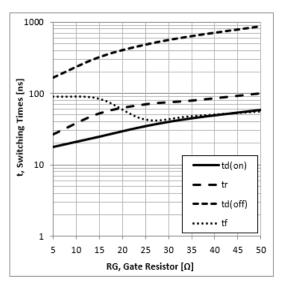


Figure 10: Typical Switching Time VS. RG, TC=25°C, L=100uH,VCE=600V,VGE=15V,IC=30A

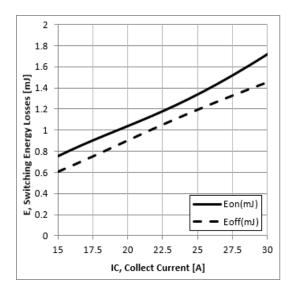


Figure 11: Typical Energy Loss VS. IC,TC=25 $^{\circ}$ C, L=100uH, VCE=600V, VGE=15V,RG=15 $^{\Omega}$ 

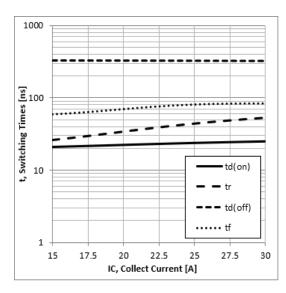


Figure 12: Typical Switching Time VS. IC,TC=25 $^{\circ}$ C, L=100uH,VCE=600V,VGE=15V,RG=15 $^{\circ}$ 





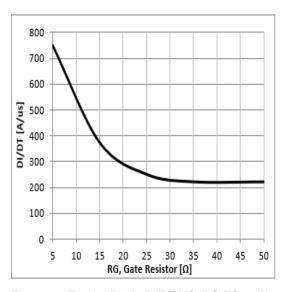


Figure 13: Typical Diode DI/DT VS. RG,TC=25℃ VCC=600V, VGE=15V, IF=30A

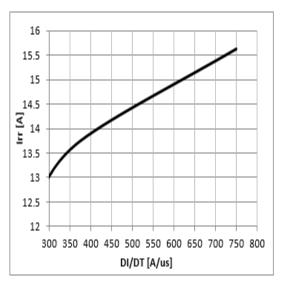


Figure 14: Typical Diode IRR VS. DI/DT,TC=25°C VCC=600V,VGE=15V, IF=30A

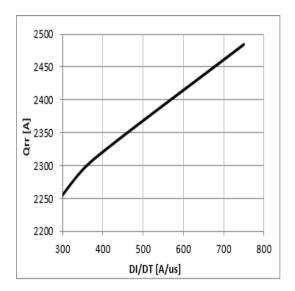


Figure 15: Typical Diode Qrr VS. DI/DT,TC=25℃ VCC=600V, VGE=15V, IF=30A

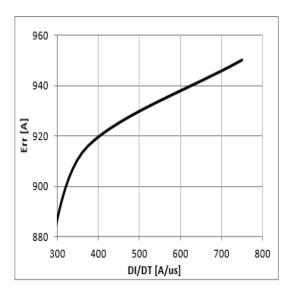


Figure 16: Typical Diode Err VS. DI/DT,TC=25℃ VCC=600V, VGE=15V, IF=30A



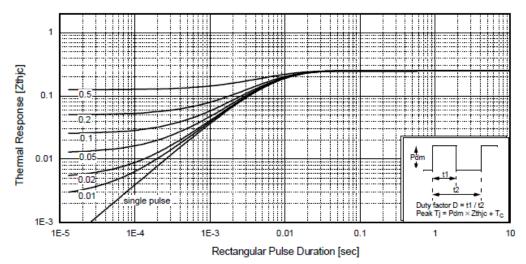
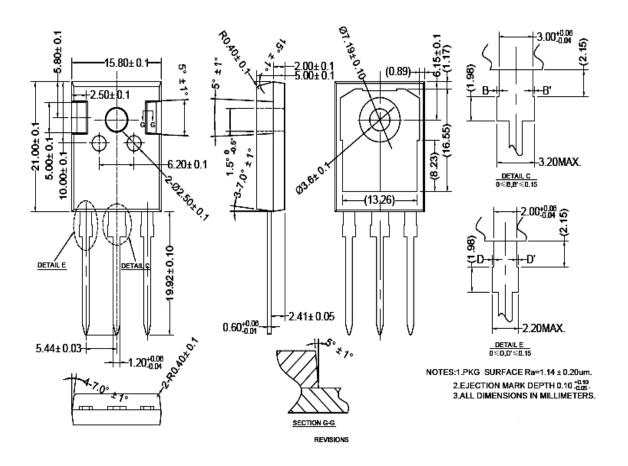


Figure 17: Normalized Transient Thermal Impedance, junction-to-case

Note1.Duty factor D=t1/t2 Note2: peak TJ=PDM × Zthjc + TC



#### **TO247 PACKAGE OUTLINE**



会差标注	会差值	表面粗糙度
0	±0.2	Ra3.2~6.3
0.0	±0.1	Ra1.6~3.2
0.00	±0.01	Ra0.8~1.6
0.000	±0.005	Ra0.4~0.8
0.0000	±0.002	Ra0.2~0.4

#### 0≤D,D'≤0.15

NOTES:1.PKG SURFACE Ra=1.14 ± 0.20um. 2.EJECTION MARK DEPTH 0.10 ±0.06 3.ALL DIMENSIONS IN MILLIMETERS.



### JNG30N120HS2

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